<u>S/N 09/834,751</u> <u>PATENT</u>

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

 Applicant:
 Sergey A. Velichko et al.
 Examiner:
 Craig Steven Miller

 Serial No.:
 09/834,751
 Group Art Unit:
 2857

 Filed:
 Auril 13, 2001
 Docket:
 303.750US1

Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

MS Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 et. seq., the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Supplemental Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(c)(2), Applicants hereby authorize the Commissoner to charge the fee of \$180.00 as set forth in 37 C.F.R. §1.17(p), to Deposit Account No. 19-0743. Please charge any additional fees or credit any overpayment to Deposit Account No. 19-0743. The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Pursuant to 37 C.F.R. 1.98(a)(2), Applicant believes that copies of cited U.S. Patents and Published Applications are no longer required to be provided to the Office. Notification of this change was provided in the United States Patent and Trademark Office OG Notices dated October 12, 2004. Thus, Applicant has not included copies of any US Patents or Published Applications cited with this submission. Should the Office require copies to be provided, Applicant respectfully requests that notice of such requirement be directed to Applicant's belowsigned representative. Applicant acknowledges the requirement to submit copies of foreign patent documents and non-patent literature in accordance with 37 C.F.R. 1.98(a)(2).

Respectfully submitted.

SERGEY A. VELICHKO ET AL.

By their Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A. P.O. Box 2938 Minneapolis, MN 55402

(612) 349-9581

Date Apr. 26 66

By John M. Dahl

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Substitute for form 1449A/PTO amalete / Known INFORMATION DISCLOSURE Application Number 09/834 751 STATEMENT BY APPLICANT Filing Date April 13, 2001 Use as many sheets as necessary First Named Inventor Velichko, Sergey Group Art Unit 2857 Examiner Name Miller, Craig Attorney Docket No: 303.750US1 Sheet 1 of 1

HE DATENT DOCUMENTS

| Examiner Initial * | USP Document Number | Publication Date | Name of Patentee or Applicant of cited Document | Filing Date If Appropriate |
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OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS FUKUDA, E., et al., "Advanced Process Control System Description of an EasyFUKUDA, E., et al., "Advanced Process Control System Description of an Easy-Examine Cite to-use Control System Incorporating Pluggable Modules", IEEE Intn'l Symposium on Semiconductor Manufacturing Conference Proceesings, (Oct. 11-13, 1999),321-324

DATE CONSIDERED EXAMINER